

Agilents WEBINARER i JANUAR 2012.

Agilent vil hver måned holde et antall gratis webinarer, (web seminarer), hver måned på forskjellige måleløsninger for høy aktuelle teknologi temaer.

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(Dersom ikke registreringsknappen fungerer så klikk på full URL nedenfor)

Debug Digital Designs Faster with Advanced Parametric Triggering



Debug Digital Designs Faster with Advanced Parametric Triggering

Web Seminar

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Agilent Technologies invites you to our live web seminar so that you can stay up to date with the latest technologies and solutions.

When: 11th January at 15:30 CET

The Presenter:

Maryjane Hayes

Where: Online

Why this web seminar is important

Although fast waveform update rates can often reveal signal integrity problems, capturing intermittent parametric circuit problems while using a scope's standard edge triggering mode is still based on statistical odds. Not only can advanced parametric triggering help synchronize oscilloscope acquisitions and display on known complex signal activity, but this type of triggering can also be used to test for signal parametric violation conditions such as setup & hold time violations, edge speed violations, pulse amplitude violations (runts), pulse width violations, etc.

Agilent's new DSO/MSO3000 X-Series InfiniiVision oscilloscopes come standard with a variety of advanced parametric triggering and search/navigation capabilities. During this presentation you will learn the meaning of each of these violation signal conditions, as well as how to setup the scope to trigger on and test for a variety of parametric signal violation conditions using the scope's built-in training signals and advanced triggering/search/navigation capabilities.

Who should view this web seminar

R&D engineers looking to debug and/or characterize intermittent circuit problems.

Register now



Maryjane Hayes is the InfiniiVision Oscilloscopes Product Manager in the Digital Test Division. She is responsible for bringing new and innovative system verification and validation solutions to students and engineers in the electronics industry.

Maryjane's 10 years of years experience at Agilent include three years in Technical Support, three years in Sales Development for high volume oscilloscopes and the past four years as a Product Marketing manager.

Lenke til oversikt og registrering:

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Overcome High Speed Digital Design Challenges Webcast Series

View [high speed digital design news](#) in your browser.



Webcast Series: Overcome High Speed Digital Design Challenges

Improve your time-to-market using modern techniques

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Greetings,

When digital signals reach gigabit/sec speeds, the unpredictable becomes the norm. For a successful design project, you'll need techniques taken from communication science (like adaptive equalization) and tools taken from microwave engineering (like field solvers) to overcome the three main design challenges: signal integrity, power integrity and EMI/EMC. In this **series of complimentary webcasts**, we'll show you how to improve your time-to-market using these modern techniques.

1) Overcome Signal Integrity Challenges

December 15, 2011 at 7:00 am or 10:00 am PT

To mitigate channel impairments in multigigabit/sec regimes, modern SERDES use signal processing techniques such as receive equalization. You can tune parameters to optimum values in the field via

Application note: Simulating High-Speed Serial Channels with IBIS-AMI Models

This paper reviews the benefits and limitations of using IBIS models in end-to-end simulations of multigigabit/sec chip-to-chip serial links and introduces the new AMI extensions to the latest IBIS version 5.0 specification. It also explains how to perform simulations of a typical backplane system using Advanced Design System 2011 (ADS2011) tools.

[read application note >](#)

register settings. However, to find optimum values, you need to explore the design space. For a variety of reasons, conventional SPICE-like transient simulations are impractical. In this webcast, you'll learn how channel simulation and IC models based on the emerging IBIS 5.0 AMI flow can overcome these challenges.

2) Overcome PI Challenges on Perforated Power/Ground Planes

January 19, 2012 at 7:00 am or 10:00 am PT

Traditional power integrity tools fail when applied to PCBs and packages with heavily perforated power/ground planes because they were built for high-layer-count boards that can afford the luxury of solid power/ground planes. In this webcast, we'll explain a different approach that's applicable to PI analysis on low-cost consumer boards whose power/ground planes are perforated with signal traces.

3) Introduction to EMI/EMC Challenges and Their Solutions

February 16, 2012 at 7:00 am or 10:00 am PT

Discovery of an EMI/EMC failure late in your project can force you to adopt makeshift solutions that add unit cost and delay time to market. In this webcast, we explain the causes of EMI/EMC and propose a proactive methodology called "Virtual EMI lab." This method uses EM simulation to identify and mitigate issues early in the design when many more design options are available.

Register for the webcast series today. **Contact us** for help choosing the best tools for overcoming your high speed digital design challenges.

Sincerely,

Agilent Technologies

Stay up to date on high speed digital news

Sign up for the High Speed Digital blog. This blog offers tips, tricks, and tutorials to help ensure signal integrity on high speed digital chip-to-chip data links.

[visit blog >](#)

Download self-guided version of high speed digital workshop

We've run a series of workshop events in several US cities. If you attended and want to review the materials, or if you weren't able to attend and want to use the materials in a self-guided way, click the button below.

[get workshop materials >](#)

High Speed Digital Design Webcast Series

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Modern Remote and Wireless Test Setup and Considerations



Modern Remote and Wireless Test Setup and Considerations

Web Seminar

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Agilent Technologies invites you to our live web seminar so that you can stay up to date with the latest technologies and solutions.

When: 24th January at 15:00 CET

Where: Online

The Presenter: Neil Forcier

Why this web seminar is important

In our global society we continue to become more and more connected wirelessly to each other and to data or information. The basis or foundation of our global connectivity is Ethernet or LAN which is a hard wired networking standard. We have witnessed and are still witnessing an explosion in low cost wireless devices that sit on the edge of LAN networks and handheld portable wireless computing devices that allow us to access a LAN network from anywhere.

In this presentation we will discuss how we can use these various off the shelf devices to access LXI instruments wirelessly from anywhere at any time and some of the security tradeoffs associated with ubiquitous access.

Who should view this web seminar

Test designers and engineers, R&D engineers, design validation engineers, field and maintenance supervisors and engineers, system designers and engineers, instrumentation specialists and engineers.

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Neil Forcier served in the US Navy as an Electronic Test Equipment Calibration Technician on board the USS Harry S Truman CVN-75. He earned his bachelors degree in engineering from the Pennsylvania State University, University Park campus.

Neil is currently working as an Application Engineer for the System Products Division at Agilent Technologies. Currently at Agilent his areas of focus include remote instrument control, timing measurements, and advanced power applications.

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